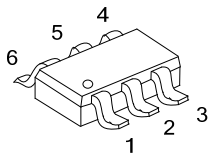
U74LVC1G373

Preliminary ***CMOS IC***

SINGLE D-TYPE LATCH WITH 3-STATE OUTPUT



SOT-363

■ DESCRIPTION

The **U74LVC1G373** device is a single D-type latch designed for 1.65V to 5.5V V_{CC} operation.

This device is particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers. While the latch-enable (LE) input is high, the Q outputs follow the data (D) inputs. When LE is taken low, the Q outputs are latched at the logic levels set up at the D inputs.

$\overline{OE}$ does not affect the internal operations of the latch. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

■ FEATURES

* Wide supply voltage range from 1.65V to 5.5V
* Inputs accept voltages up to 5.5V
* I_{OFF} supports partial-power-down mode
* Low static power consumption; I_{CC}=10μA (Max.)

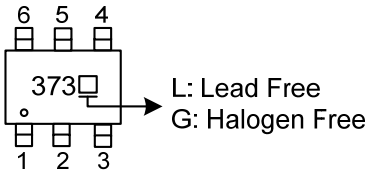
■ ORDERING INFORMATION

Ordering Number		Package	Packing
Lead Free	Halogen Free		
U74LVC1G373L-AL6-R	U74LVC1G373G-AL6-R	SOT-363	Tape Reel

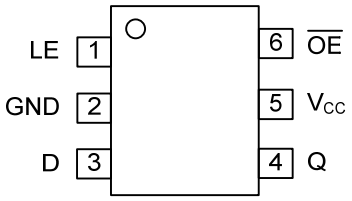
U74LVC1G373G-AL6-R
(1)Packing Type
(2)Package Type
(3)Green Package

(1) R: Tape Reel
(2) AL6: SOT-363
(3) G: Halogen Free and Lead Free, L: Lead Free

■ MARKING



■ PIN CONFIGURATION



■ PIN DESCRIPTION

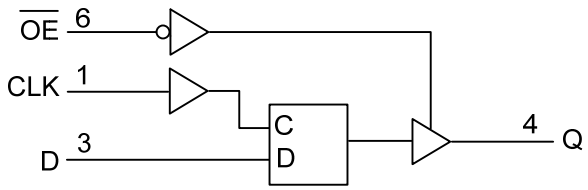
PIN NO.	PIN NAME	I/O	DESCRIPTION
1	LE	I	Latch Enable; output follows D input when high
2	GND	-	Ground
3	D	I	D latch input
4	Q	O	Q latch output
5	V_{CC}	-	Positive supply
6	$\overline{OE}$	I	Active low output enable; Hi-Z output when high

■ FUNCTION TABLE

INPUT($\overline{OE}$)	INPUT(LE)	INPUT(D)	OUTPUT(Q)
L	H	L	L
L	H	H	H
L	L	X	Q_0
H	X	X	Hi-Z

Note: H: HIGH voltage level, L: LOW voltage level, Q_0: No Change, Hi-Z: High Impedance.

■ LOGIC DIAGRAM (positive logic)



■ ABSOLUTE MAXIMUM RATING (T_A=25°C, unless otherwise specified)

PARAMETER	SYMBOL	CONDITIONS	RATINGS	UNIT
Supply Voltage	V_{CC}		-0.5 ~ +6.5	V
Input Voltage	V_{IN}		-0.5 ~ +6.5	V
Output Voltage	V_{OUT}	Output in the high or low state	-0.5 ~ V_{CC} +0.5	V
		Output in the power-off state	-0.5 ~ +6.5	V
Continuous V_{CC} or GND Current	I_{CC}		±100	mA
Continuous Output Current	I_{OUT}		±50	mA
Input Clamp Current	I_{IK}	V_{IN}<0V	-50	mA
Output Clamp Current	I_{OK}	V_{OUT}<0V	-50	mA
Storage Temperature Range	T_{STG}		-65 ~ +150	°C

Note: Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

■ RECOMMENDED OPERATING CONDITIONS (T_A=25°C, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Supply Voltage	V_{CC}	Operating	1.65		5.5	V
		Data retention only	1.5			V
Input Voltage	V_{IN}		0		5.5	V
Output Voltage	V_{OUT}		0		V_{CC}	V
Input Transition Rise or Fall Rate	Δt/Δv	V_{CC}=1.8V±0.15V, 2.5V±0.2V			20	ns/V
		V_{CC}=3.3V±0.3V			10	ns/V
		V_{CC}=5V±0.5V			5	ns/V
Operating Temperature	T_A		-40		+125	°C

■ ELECTRICAL CHARACTERISTICS (T_A=25°C, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
High-level Input Voltage	V_{IH}	V_{CC}=1.8±0.15V	0.65×V_{CC}			V
		V_{CC}=2.5±0.2V	1.7			V
		V_{CC}=3.3±0.3V	2			V
		V_{CC}=5±0.5V	0.7×V_{CC}			V
Low-level Input Voltage	V_{IL}	V_{CC}=1.8±0.15V			0.35×V_{CC}	V
		V_{CC}=2.5±0.2V			0.7	V
		V_{CC}=3.3±0.3V			0.8	V
		V_{CC}=5±0.5V			0.3×V_{CC}	V
High-Level Output Voltage	V_{OH}	V_{CC}=1.65 ~ 5.5V, I_{OH}=-100μA	V_{CC}-0.1			V
		V_{CC}=1.65V, I_{OH}=-4mA	1.2			V
		V_{CC}=2.3V, I_{OH}=-8mA	1.9			V
		V_{CC}=3.0V, I_{OH}=-16mA	2.4			V
		V_{CC}=3.0V, I_{OH}=-24mA	2.3			V
		V_{CC}=4.5V, I_{OH}=-32mA	3.8			V
Low-Level Output Voltage	V_{OL}	V_{CC}=1.65 ~ 5.5V, I_{OL}=100μA			0.1	V
		V_{CC}=1.65V, I_{OL}=4mA			0.45	V
		V_{CC}=2.3V, I_{OL}=8mA			0.3	V
		V_{CC}=3.0V, I_{OH}=16mA			0.4	V
		V_{CC}=3.0V, I_{OH}=24mA			0.55	V
		V_{CC}=4.5V, I_{OL}=32mA			0.55	V
Input Leakage Current	$I_{I(LEAK)}$	V_{CC}=1.65V ~ 5.5V V_{IN}=V_{CC} or GND			±1	μA
Power Off Leakage Current	I_{OFF}	V_{CC}=0V, V_{IN} or V_{OUT}=5.5V			±10	μA
OFF-state output current	I_{OZ}	V_{CC}=3.6V, V_{OUT}=0~5.5V			±5	μA

■ ELECTRICAL CHARACTERISTICS (Cont.)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Quiescent Supply Current	I_{CC}	V_{CC}=1.65 ~ 5.5V, V_{IN}= V_{CC} or GND, I_{OUT}=0			10	μA
Additional Quiescent Supply Current Per Input Pin	ΔI_{CC}	V_{CC}=3 ~ 5.5V, One input at V_{CC}-0.6V, other inputs at V_{CC} or GND			500	μA
Input Capacitance	C_{IN}	V_{CC}=3.3V, V_{IN}=V_{CC} or GND		3.5		pF
Output Capacitance	C_{OUT}	V_{CC}=3.3V, V_{IN}=V_{CC} or GND		6		pF

■ TIMING REQUIREMENTS

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Pulse Duration, CLK High	t_w		3.0			ns
Setup Time, Data Before CLK↓	t_{su}	V_{CC}=1.8±0.15V	2.9			ns
		V_{CC}=2.5±0.2V	2.1			ns
		V_{CC}=3.3±0.3V	1.5			ns
		V_{CC}=5±0.5V	1.5			ns
Hold Time, Data After CLK↓	t_h	V_{CC}=1.8±0.15V	3.0			ns
		V_{CC}=2.5±0.2V	1.5			ns
		V_{CC}=3.3±0.3V	1.5			ns
		V_{CC}=5±0.5V	1.5			ns

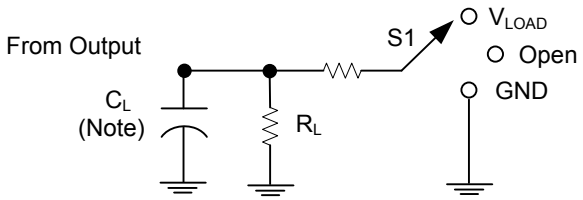
■ SWITCHING CHARACTERISTICS (T_A=25°C, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS		MIN	TYP	MAX	UNIT
Propagation delay from input (D) to output (Q)	t_{PD}	V_{CC}=1.8V±0.15V	C_L=30pF or 50pF	2.0		17	ns
		V_{CC}=2.5V±0.2V		1.5		8.5	ns
		V_{CC}=3.3V±0.3V		1.0		6.5	ns
		V_{CC}=5.0V±0.5V		1.0		4.7	ns
Propagation delay from input (LE) to output (Q)		V_{CC}=1.8V±0.15V	C_L=30pF or 50pF	2.0		17	ns
		V_{CC}=2.5V±0.2V		1.5		8.0	ns
		V_{CC}=3.3V±0.3V		1.0		6.0	ns
		V_{CC}=5.0V±0.5V		1.0		4.5	ns
Propagation delay from input ($\overline{OE}$) to output (Q)	t_{en}	V_{CC}=1.8V±0.15V	C_L=30pF or 50pF	2.0		15.2	ns
		V_{CC}=2.5V±0.2V		1.5		13.5	ns
		V_{CC}=3.3V±0.3V		1.0		12	ns
		V_{CC}=5.0V±0.5V		1.0		9.5	ns
Propagation delay from input ($\overline{OE}$) to output (Q)	t_{dis}	V_{CC}=1.8V±0.15V	C_L=30pF or 50pF	2.0		18.4	ns
		V_{CC}=2.5V±0.2V		1.0		7.9	ns
		V_{CC}=3.3V±0.3V		1.0		6.8	ns
		V_{CC}=5.0V±0.5V		1.0		5.1	ns

■ OPERATING CHARACTERISTICS (f=10MHz, TA=25°C , unless otherwise specified)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Power Dissipation Capacitance	Output enabled	C_{PD}	V_{CC}=1.8V		19		pF
			V_{CC}=2.5V		19		pF
			V_{CC}=3.3V		19		pF
			V_{CC}=5V		20		pF
	Output disabled		V_{CC}=1.8V		3		pF
			V_{CC}=2.5V		3		pF
			V_{CC}=3.3V		3		pF
			V_{CC}=5V		4		pF

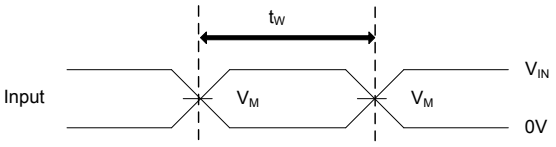
■ TEST CIRCUIT AND WAVEFORMS



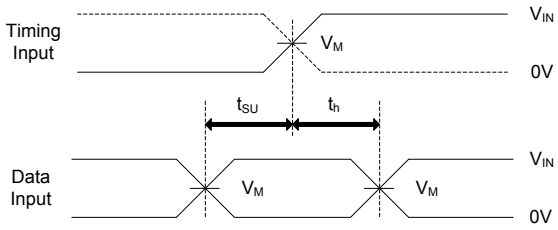
TEST	S1
t_{PLH}/t_{PHL}	Open
t_{PLZ}/t_{PZL}	V_{LOAD}
t_{PHZ}/t_{PZH}	GND

Note: C_L includes probe and jig capacitance.

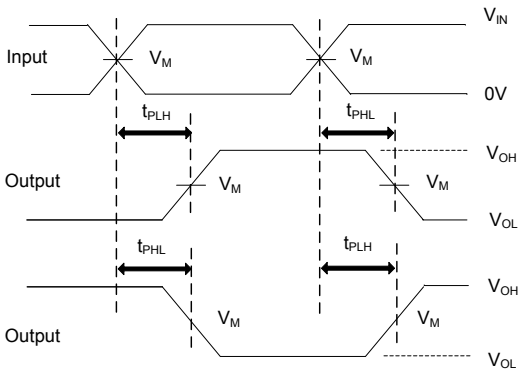
V_{CC}	V_{IN}	t_R / t_F	V_M	V_{LOAD}	C_L	R_L	V_Δ
1.8V±0.15V	V_{CC}	≤2ns	$V_{CC}/2$	$2\times V_{CC}$	30pF	1KΩ	0.15V
2.5V±0.2V	V_{CC}	≤2ns	$V_{CC}/2$	$2\times V_{CC}$	30pF	500Ω	0.15V
3.3V±0.3V	3V	≤2.5ns	1.5V	6V	50pF	500Ω	0.3V
5V±0.5V	V_{CC}	≤2.5ns	$V_{CC}/2$	$2\times V_{CC}$	50pF	500Ω	0.3V



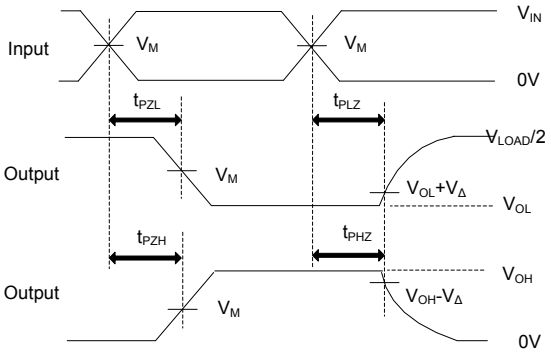
PULSE WIDTH



SETUP TIME AND HOLD TIME



PROPAGATION DELAY TIMES



ENABLE AND DISABLE TIMES

Notes: 1. C_L includes probe and jig capacitance.
2. All input pulses are supplied by generators having the following characteristics: PRR ≤10MHz, Z_O = 50Ω.